

Characterization of thin irradiated epitaxial silicon sensors for the CMS phase II pixel upgrade

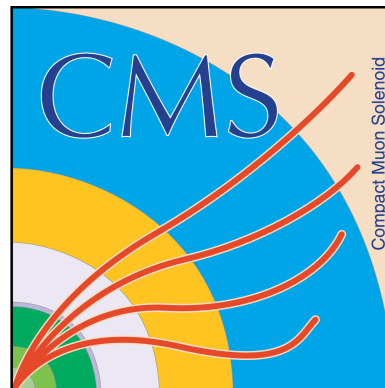
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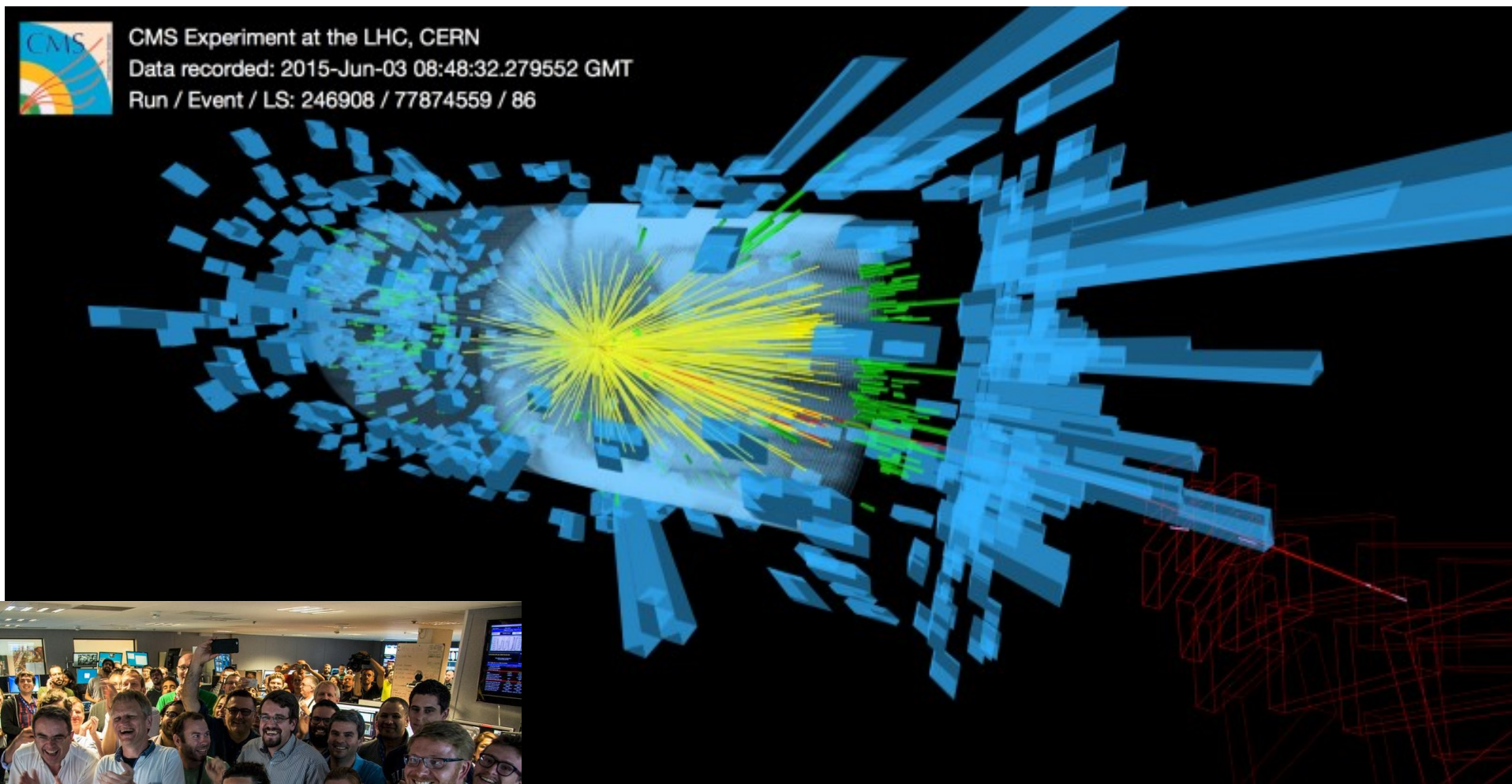


Bundesministerium
für Bildung
und Forschung



Wait, what? **Why?** ...bear with me...

LHC is back!

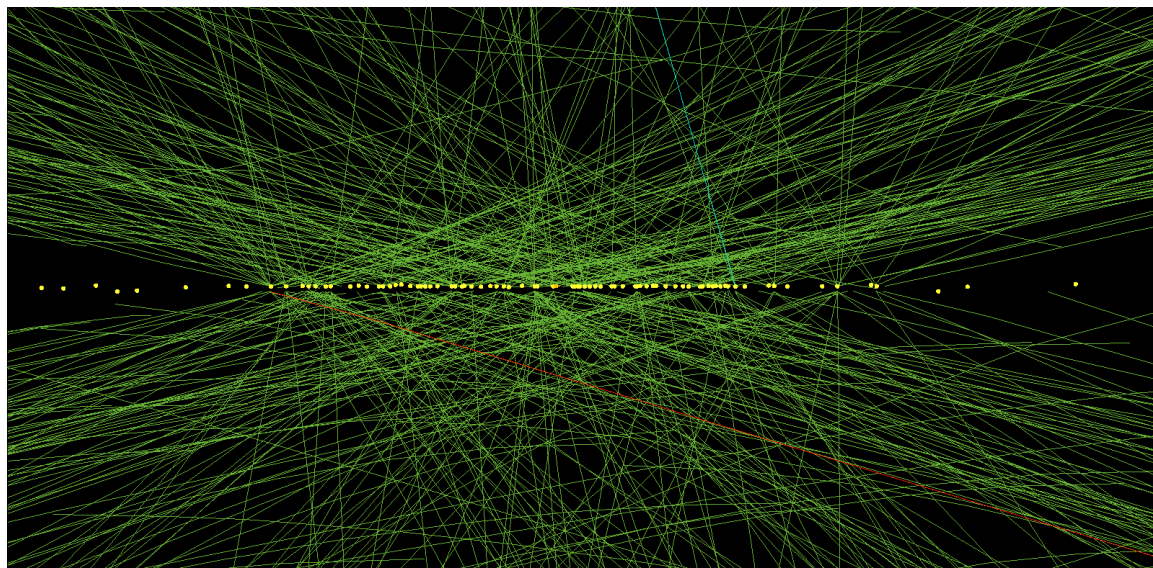


- First 13 TeV collisions in June after a long shutdown
- Luminosity being ramped up
- New period of exploration at the energy frontier

High statistics is important for many analyses:

- SUSY
- Dark matter search
- Extra dimensions
- Higgs properties
-

78 p-p collisions in high intensity run



High Luminosity LHC (2025)



- Tenfold increase in statistics: **3000 fb⁻¹**
- Luminosity increase to **5 x 10³⁴ cm⁻²s⁻¹**
- Mean number of interactions per bunch crossing **<μ> ~140** (every **25 ns**)

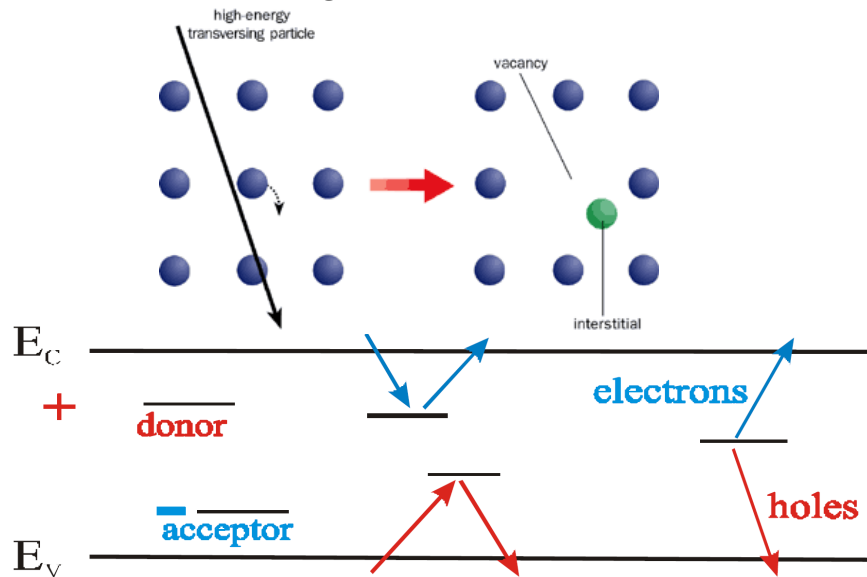
A challenge for the detector!

- Hit rate
- Radiation damage
- ...

→ Phase II tracker upgrade

Bulk damage

- Defect generation
- Change of U_{dep}
- Increase in leakage current (noise)
- Decrease in signal



charged defects

$\Rightarrow N_{\text{eff}}, V_{\text{dep}}$
e.g. donors in upper
and acceptors in
lower half of band
gap

Trapping (e and h)

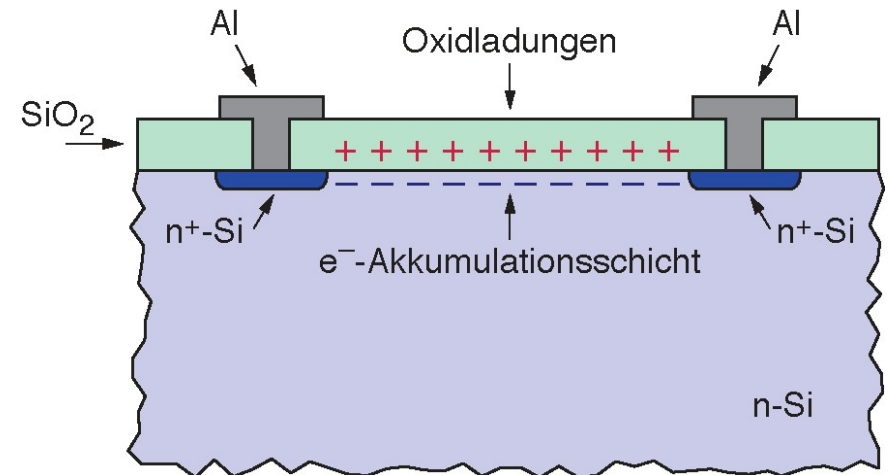
$\Rightarrow \text{CCE}$
shallow defects do not
contribute at room
temperature due to fast
detrapping

generation

$\Rightarrow$ **leakage current**
Levels close to
midgap
most effective

Surface damage

- Positive charge at the Si-SiO_2 interface
- Modification of the electric field close to the surface
 - $\rightarrow$ charge losses
 - $\rightarrow$ noise increase
 - $\rightarrow$ break down
- Creation of conductive layers
- Affects sensors and microelectronics



Relevant quantity: dose in the SiO_2

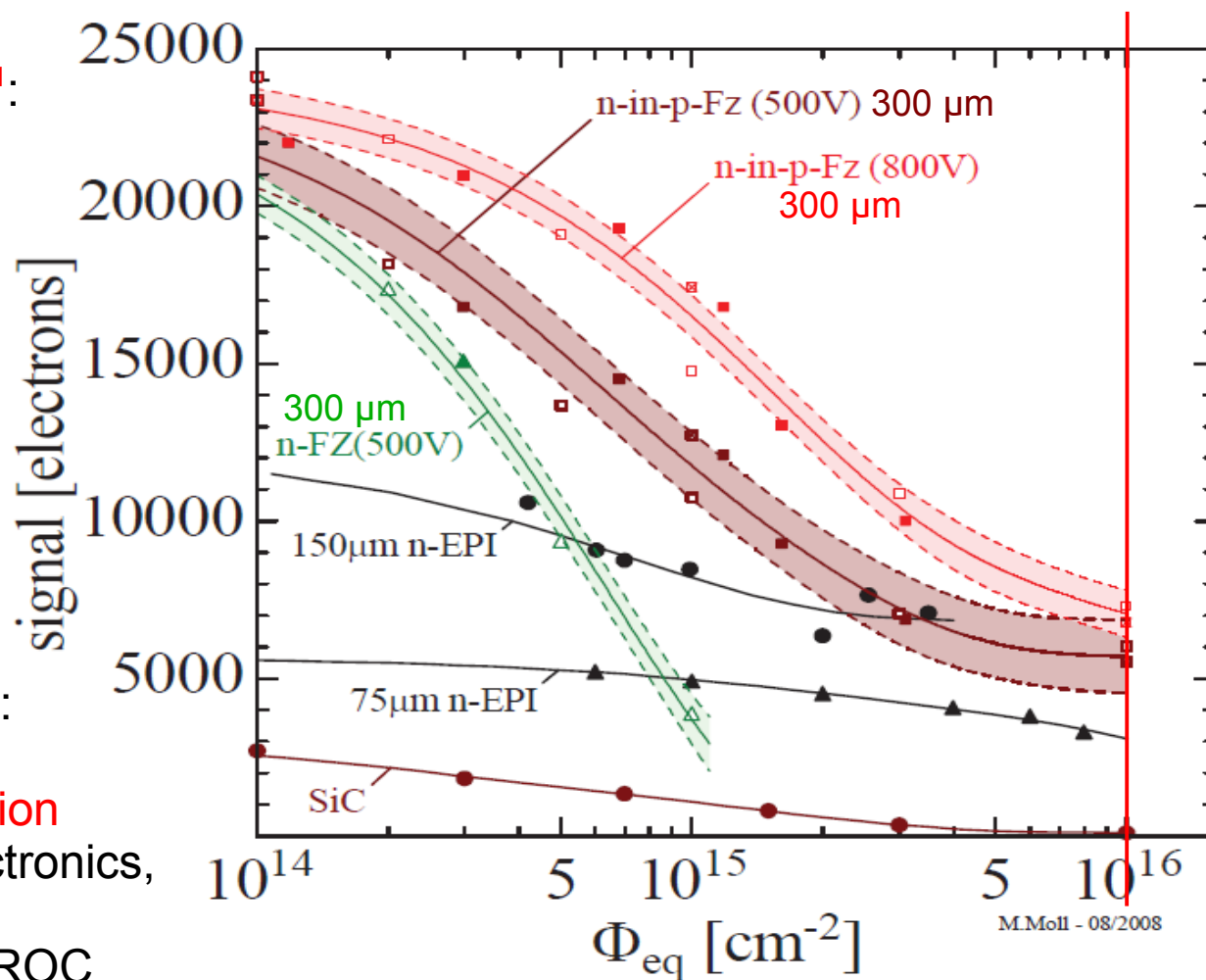
To compare damage of various particle types:
damage expressed as equivalent of 1 MeV neutrons [cm^{-2}]

2025: High Luminosity-LHC

- Innermost pixel layers after **3000 fb⁻¹**:
 - $\Phi_{eq} \sim 10^{16} \text{ cm}^{-2} \rightarrow$ bulk damage
 - **5 MGy** $\rightarrow$ surface damage
- New material / design is required,
is planar silicon a viable option?

Thin sensors compared to thick ones:

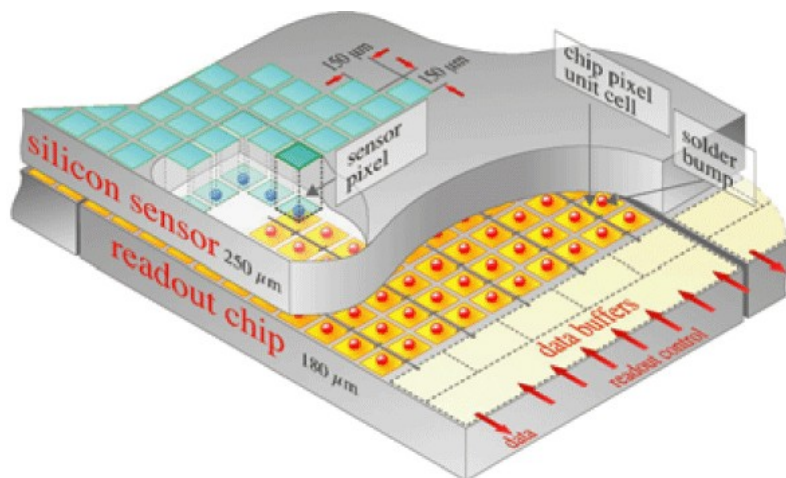
- **Less signal degradation**
- **Smaller signals** even **before irradiation**
 - $\rightarrow$ challenge for the readout electronics,
low thresholds are required
 - $\rightarrow$ **RD 53** collaboration for pixel ROC
for the HL-LHC
- $\rightarrow$ **characterization with MIP-like signals required**



Beam test of thin (100-200 μm) strip sensors to determine material characteristics

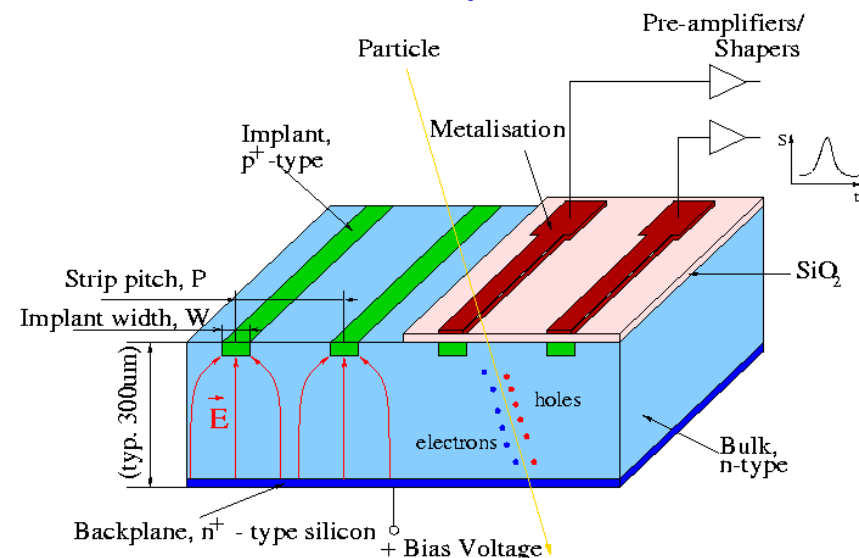
Strip detectors to study pixels?

Pixel detectors



- **Noise** level $\sim 100 e^-$ before irradiation
- **Bump bonding**
- Heat treatment to achieve connection between sensor and readout
→ **modification of sensor properties**
- Irradiation of sensor and electronics
→ **modification of electronics**

Strip detectors

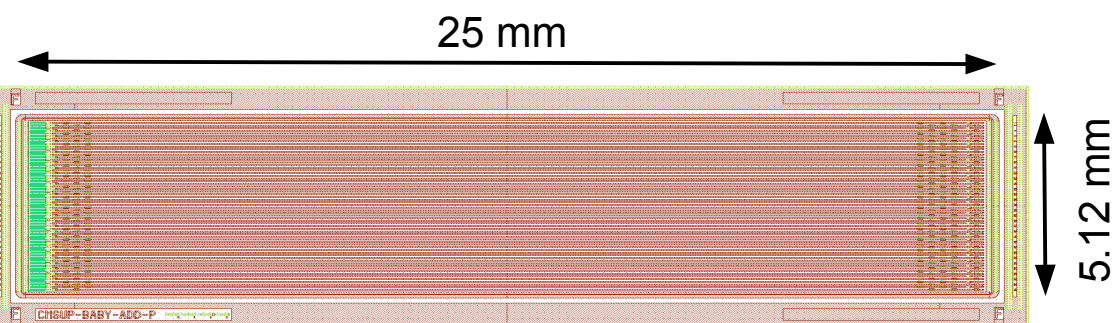
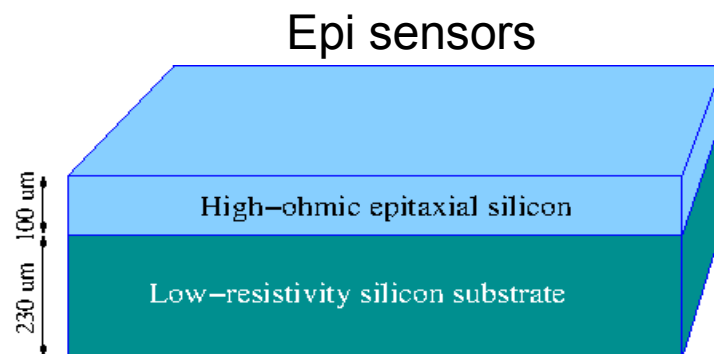
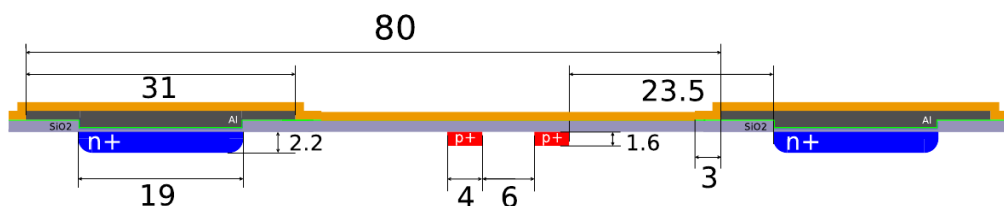


- **Noise** level $\sim 800 e^-$ before irradiation
- **Wire bonding**
- No heat treatment for connection with readout electronics
- **Separate irradiation**
- **No modification of electronics**

Beam telescope to reconstruct hit position
→ **separation of noise from signal**

- Epitaxial silicon strips of n and p type (p-spray and p-stop isolation)
- **100 μm** active thickness
- 80 μm pitch
- Irradiation with 800 MeV and 23 GeV protons
- Fluences up to $1.3 \times 10^{16} \text{ cm}^{-2}$
- MCZ and FTH with **200 μm** physical thickness
 - Only $1.3 \times 10^{16} \text{ cm}^{-2}$

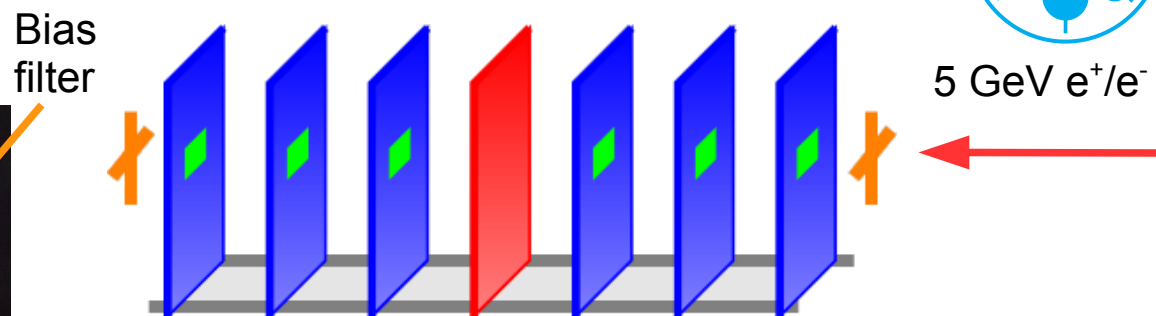
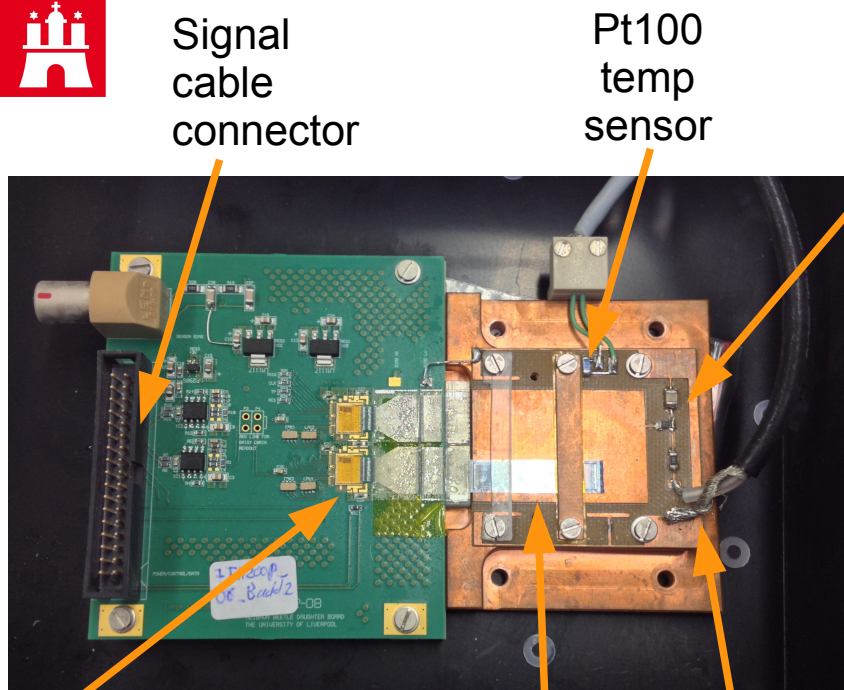
Epitaxial silicon $\rightarrow$ easy production of detectors with thin active thickness (100 μm)



64 AC coupled strips

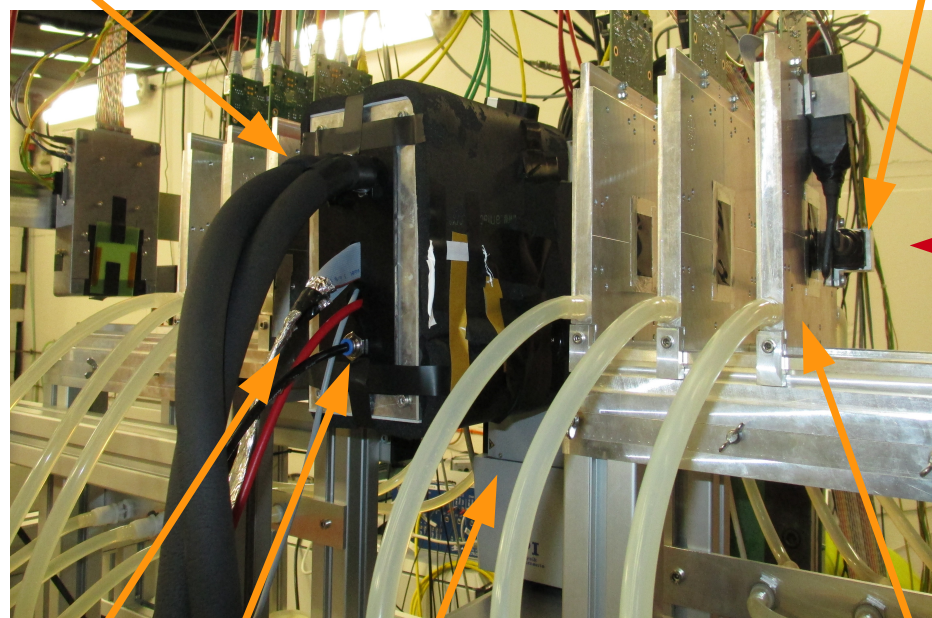
- **Results for p-type sensors**
- n-type sensors show micro discharges after irradiation (design issue)

Setup



Coolant pipes

Trigger scintillators



HV, signal and temp cables

N₂ supply

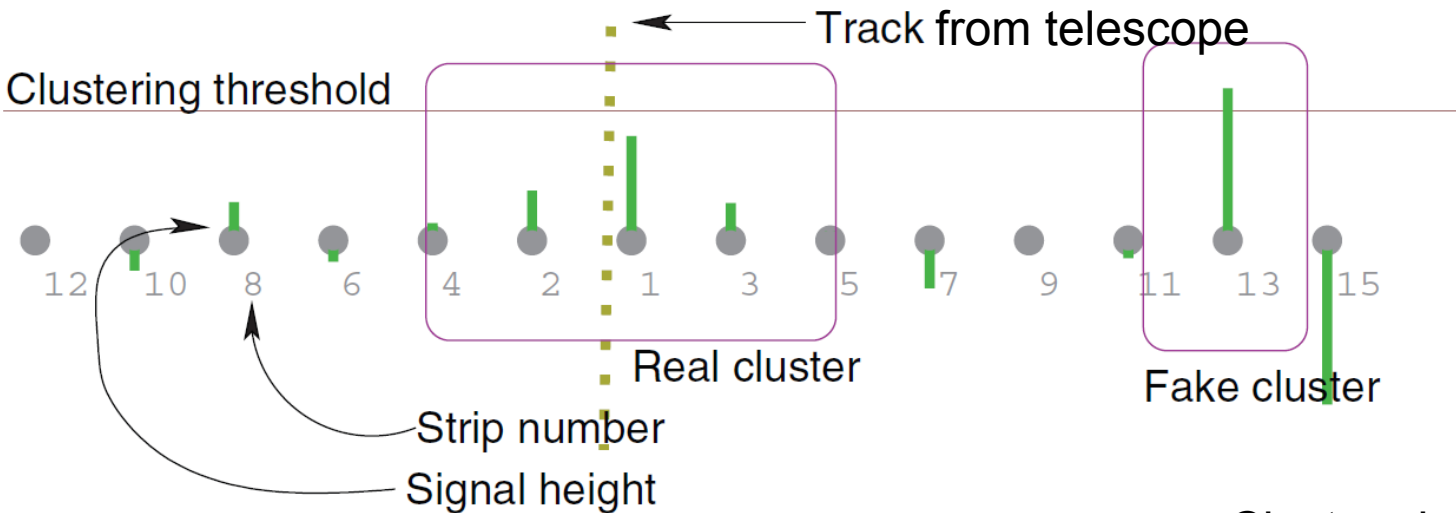
3D rotation stage

Telescope plane

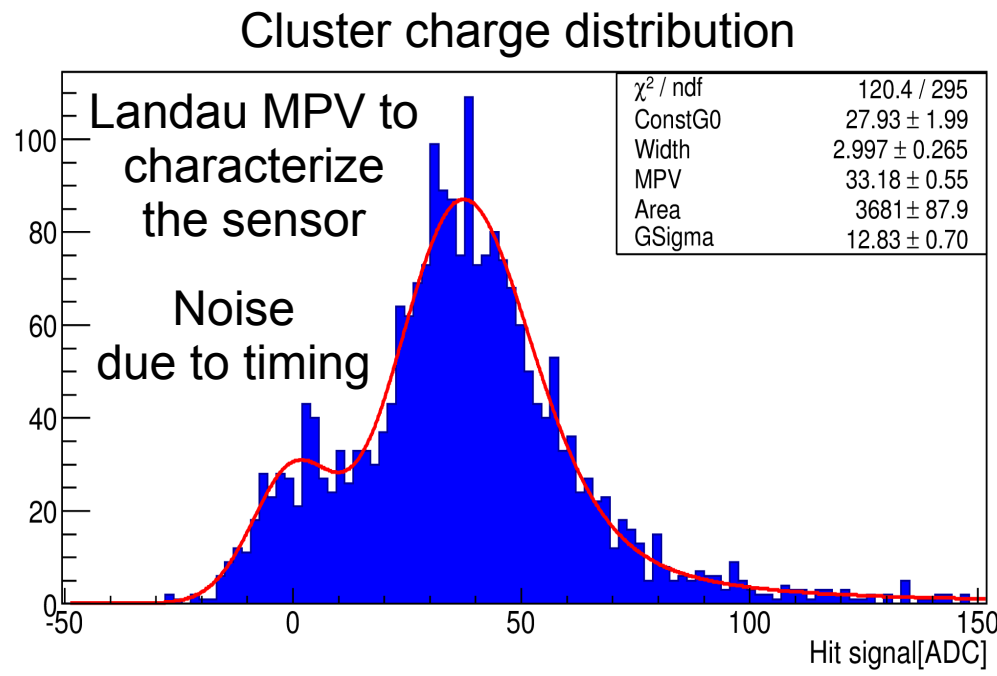
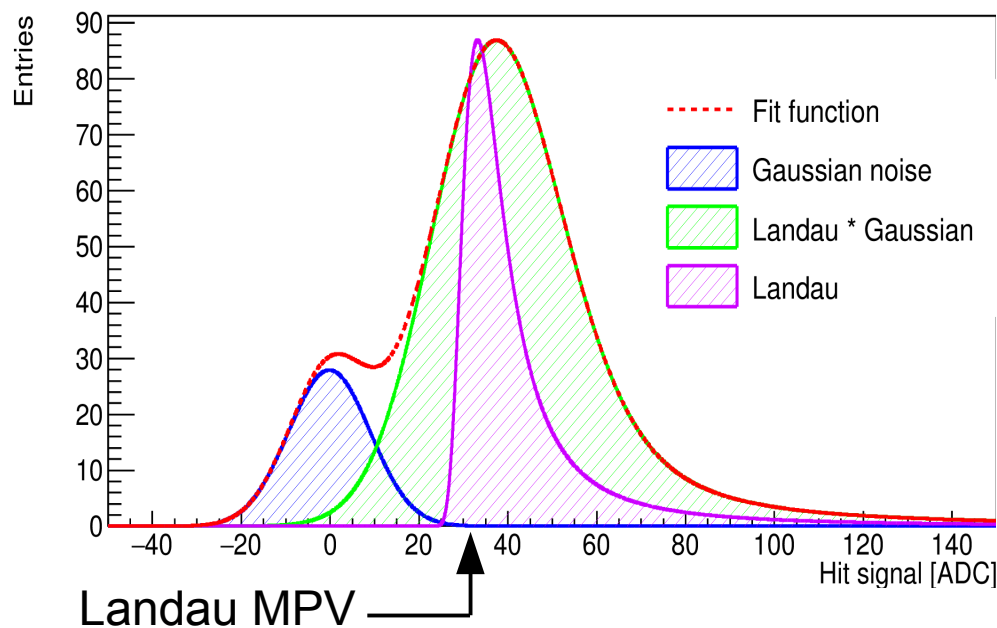
- **Beam telescope** to reconstruct tracks
 - DATURA and ACONITE
 - EUDET pixel telescopes
- **Trigger scintillators** to define events
- **Cooling** for irradiated samples
- ALiBaVa (A Liverpool Barcelona Valencia) readout system
- Readout of **positive and negative signals**
- Based on LHCb strip readout chip
- **Analog pulse height** for 2 x 128 channels

T. Mäenpää et al, IEEE 2009

Charge definition:
Sum of the signal over 5 strips, centered on the hit one

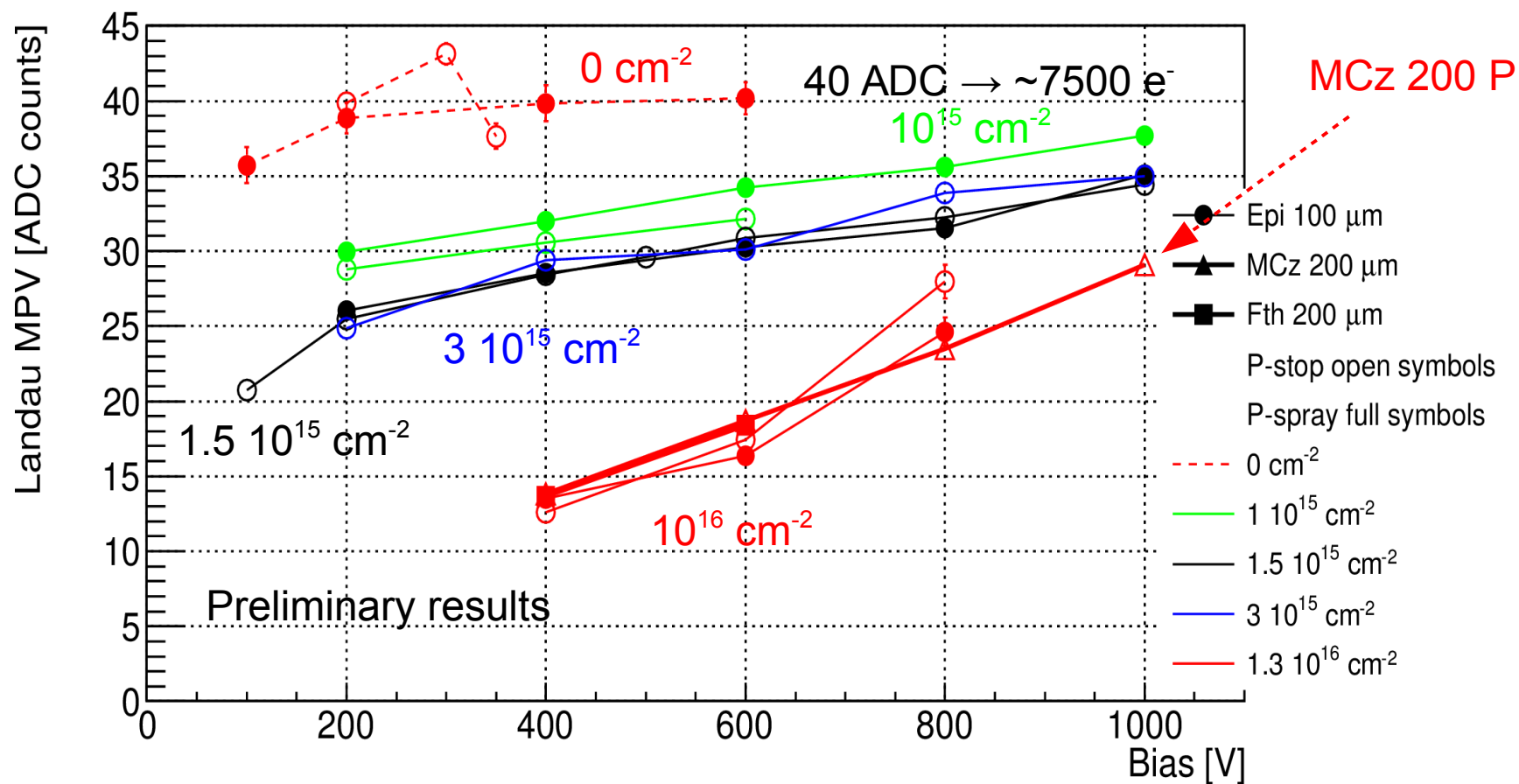


No threshold used in the analysis



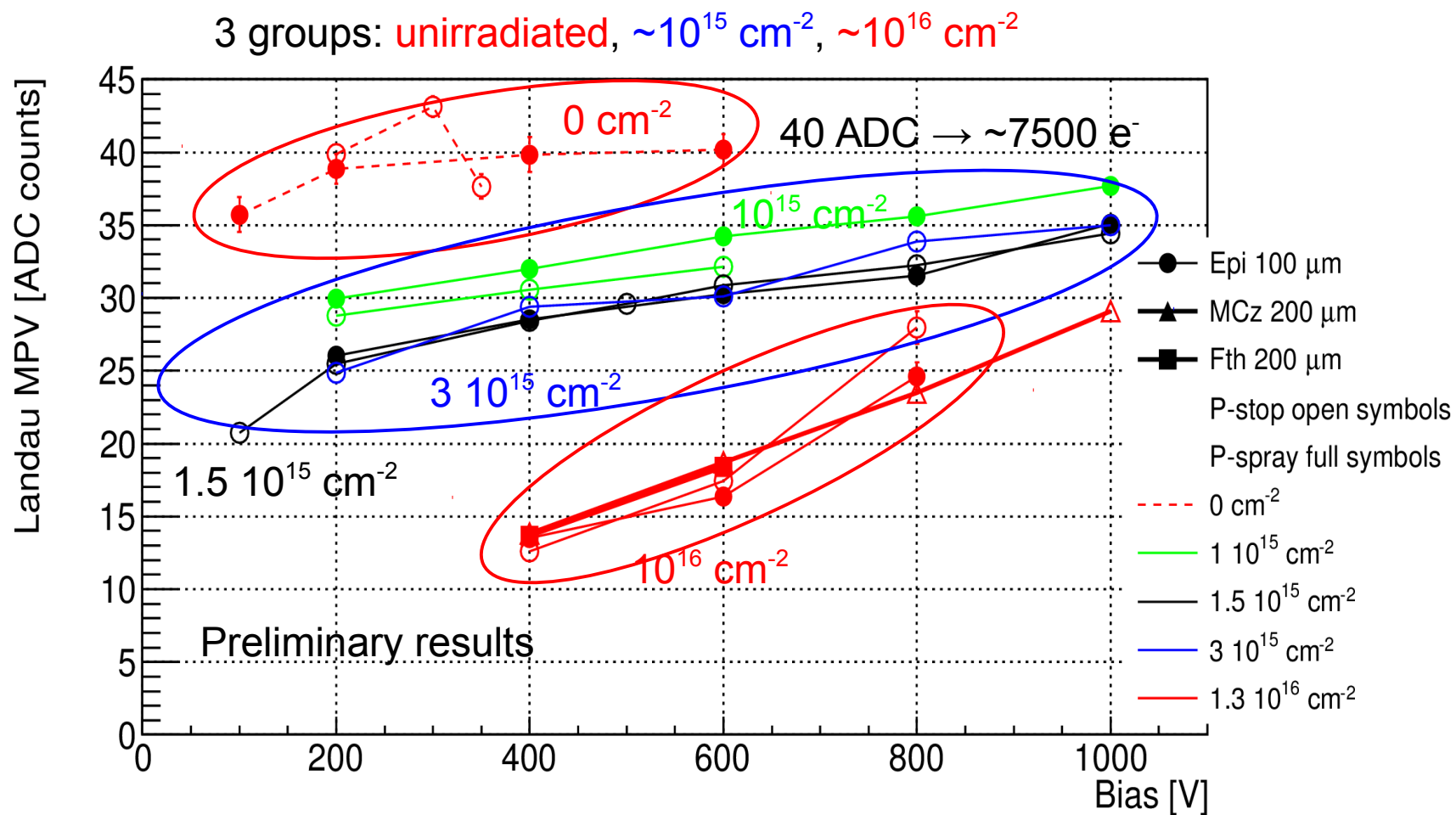
Epi100P, 23 GeV p, $3 \times 10^{15} \text{ cm}^{-2}$, -800V, -20 °C

Charge collection p-bulk



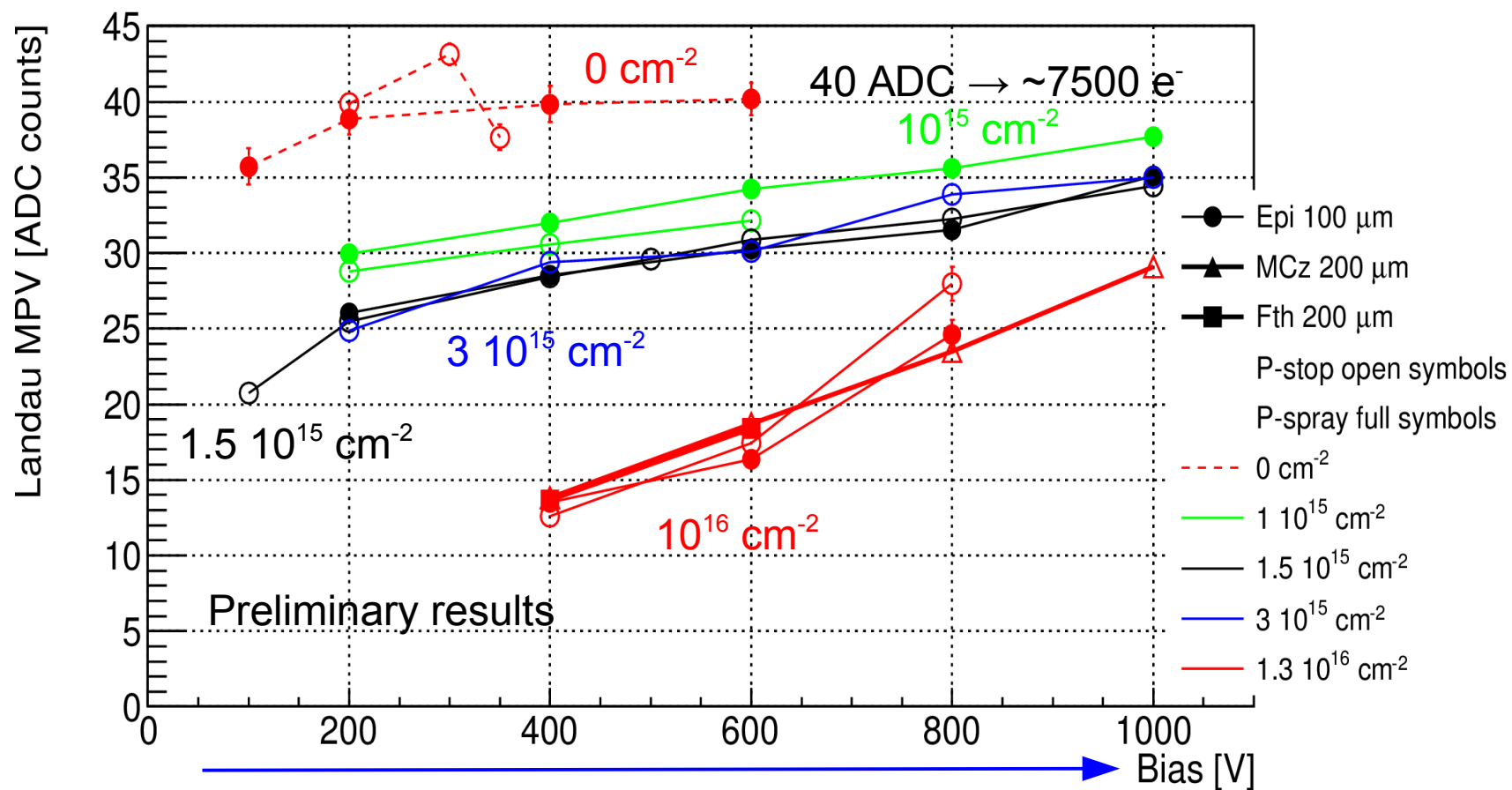


Charge collection p-bulk I



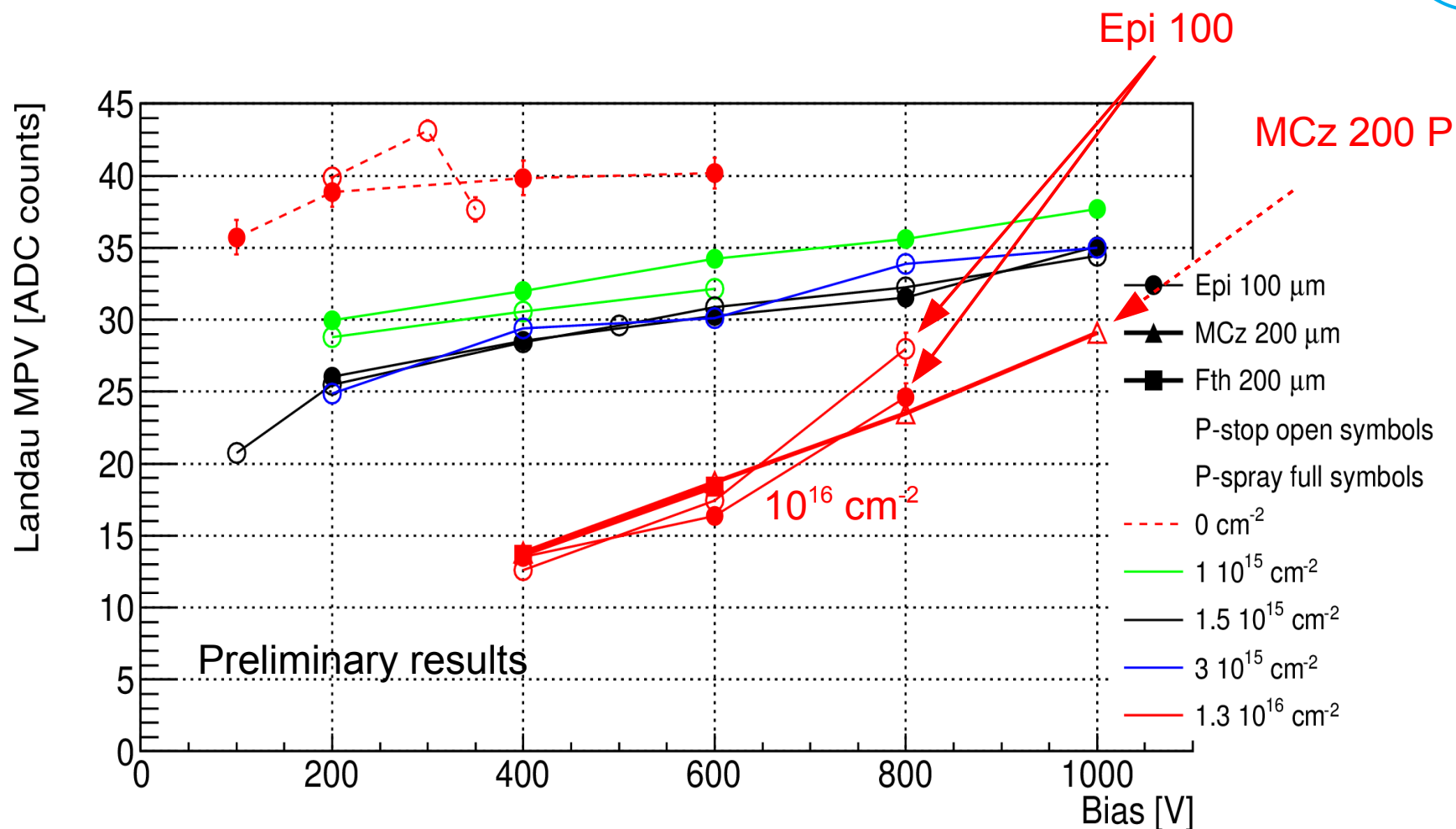
Charge collection degrades with irradiation

Charge collection p-bulk II



Charge collection increase with bias after irradiation

Charge collection p-bulk



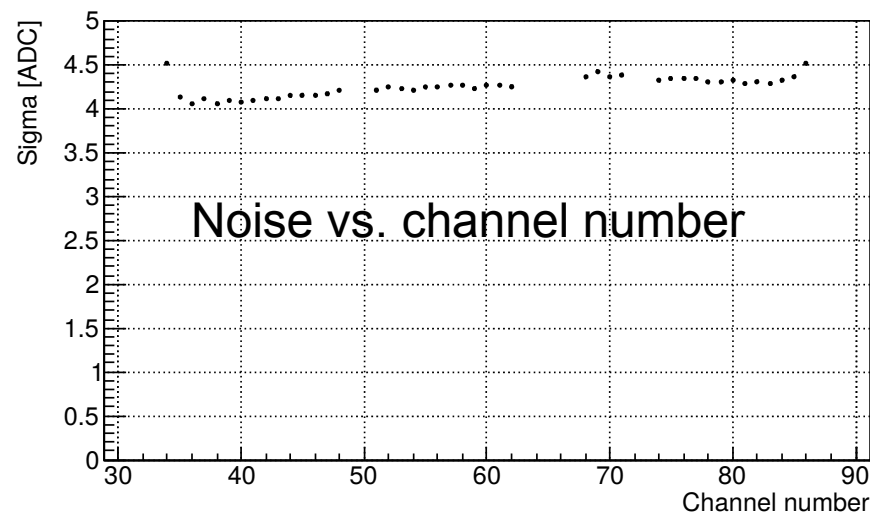
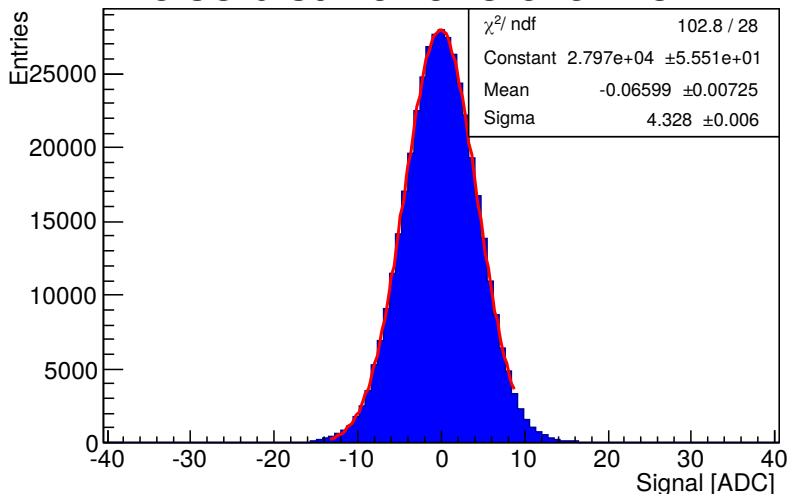
At 10^{16} cm^{-2} :

100 μm sensors $\rightarrow$ **faster signal recovery** with bias

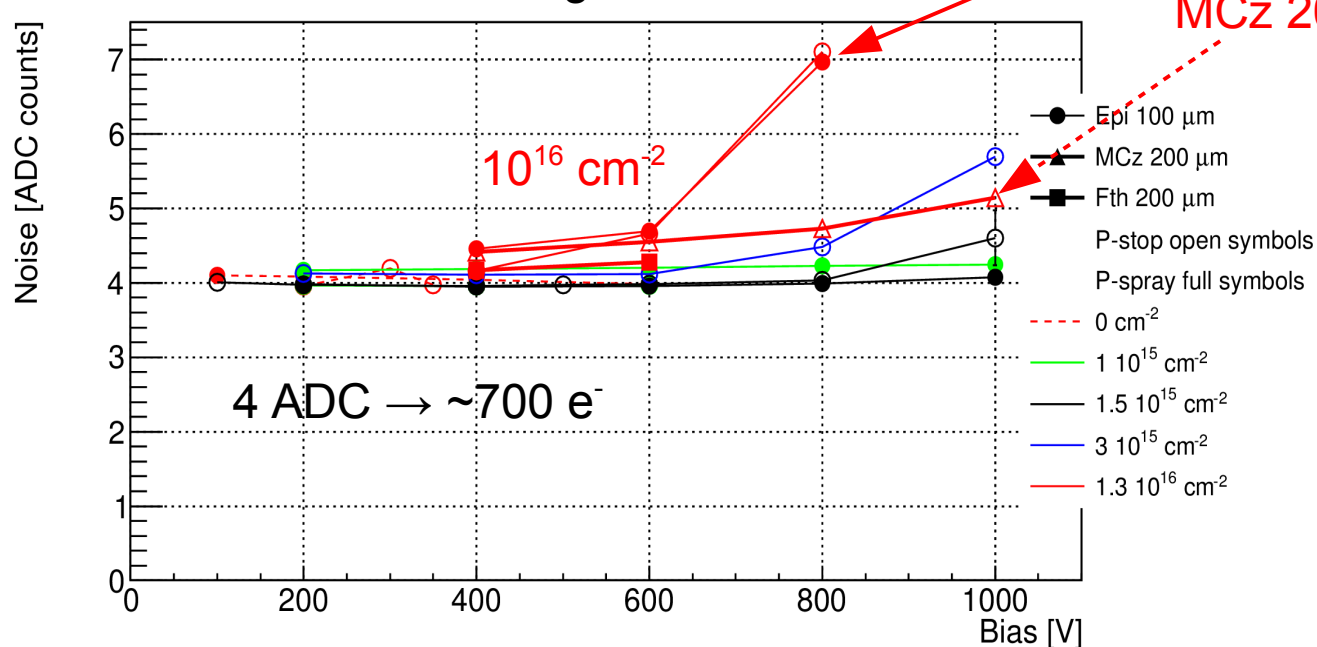
200 μm sensors $\rightarrow$ operation at **higher bias**

Similar pulse height achieved for both thicknesses

Noise distr for one channel



Mean value single channel noise



Up to $3 \times 10^{15} \text{ cm}^{-2}$:

- Noise levels similar to pre-irradiation
- Noise increase at high bias

At 10^{16} cm^{-2} :

- 100 $\mu\text{m} \rightarrow$ higher noise
 $\rightarrow$ charge multiplication?
- 200 $\mu\text{m} \rightarrow$ better noise figure

Epi100P, 23 GeV p, $3 \times 10^{15} \text{ cm}^{-2}$, -800V, -20 °C

The thin sensors show promising results:

- **100 μm** , p-bulk
 - Charge collection efficiency of $\sim 65\%$ after a fluence of 10^{16} cm^{-2}
 - **Signal** increase with bias 😊
 - **Noise** increase at high bias 😞
 - Good candidates for outer pixel layers (fluence $\sim 10^{15} \text{ cm}^{-2}$)
 - Further studies needed for operation after a fluence of 10^{16} cm^{-2}
- **200 μm** , p-bulk
 - Charge collection efficiency of $\sim 35\%$ after a fluence of 10^{16} cm^{-2}
 - Compared to 100 μm sensors:
 - Slower **signal** increase with bias 😞
 - Smaller **noise** 😊

Can 150 μm sensors be a good compromise?
 → next common CMS sensor submission will give the answer!

Special thanks to the test beam shifters!

Thank you for your attention!



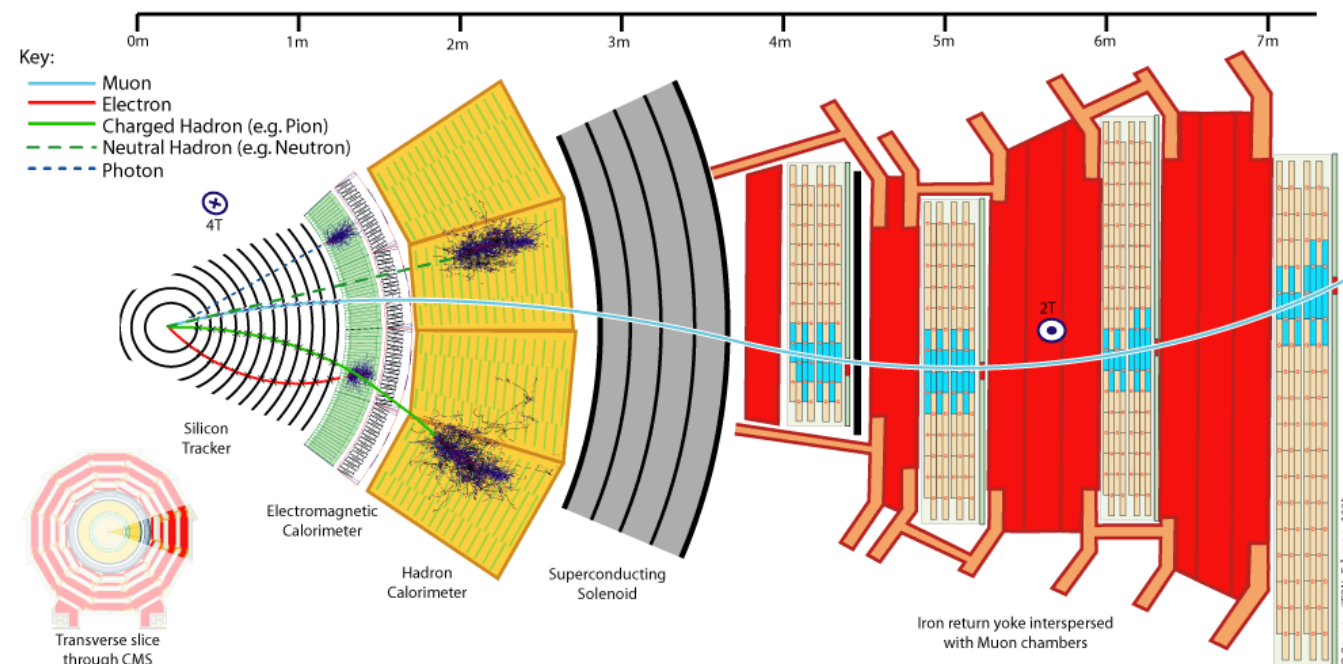
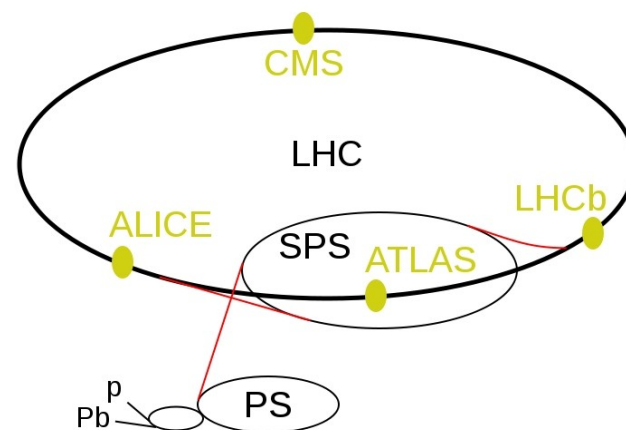
Backup

LHC:

- Large Hadron Collider
- Proton-proton and heavy ions collider
- 27 km circumference
- Operating at 13 TeV
- 4 interaction points

CMS:

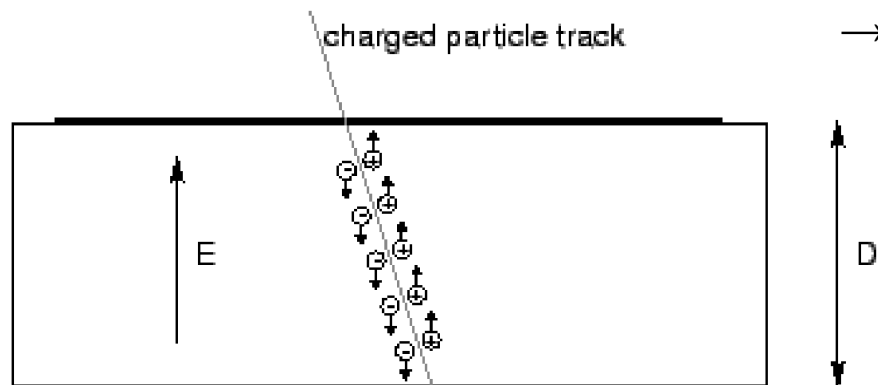
- Compact Muon Solenoid
- General purpose experiment
- High luminosity interaction point



Achievements:

- Tests of the standard model
- Discovery of the Higgs boson by ATLAS and CMS

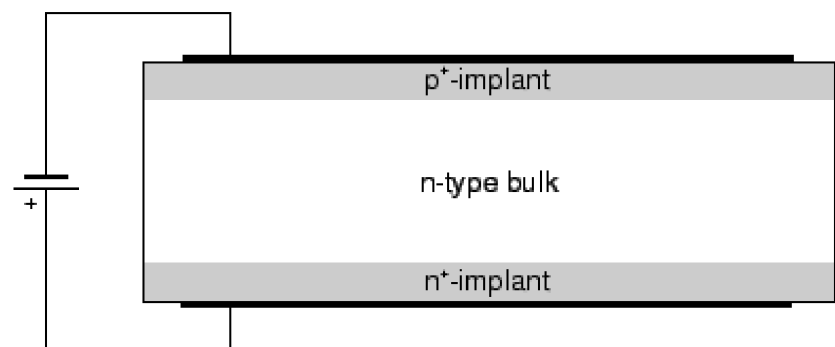
Solid state ionization detector



- Small mean ionization energy (3.6 eV / eh)
→ **high signal, small thickness**
- Small thickness → **fast signal**

Thermally generated current

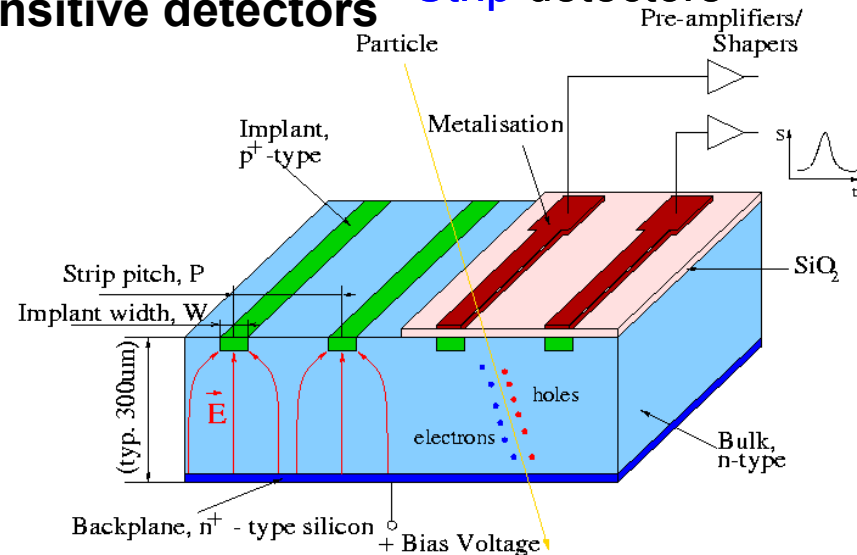
Rectifying junction (diode)



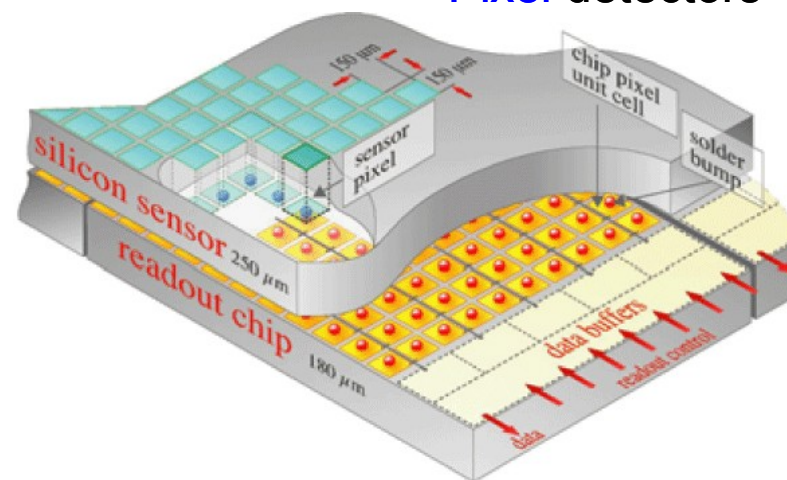
Structuring the electrodes

→ **position sensitive detectors**

Strip detectors

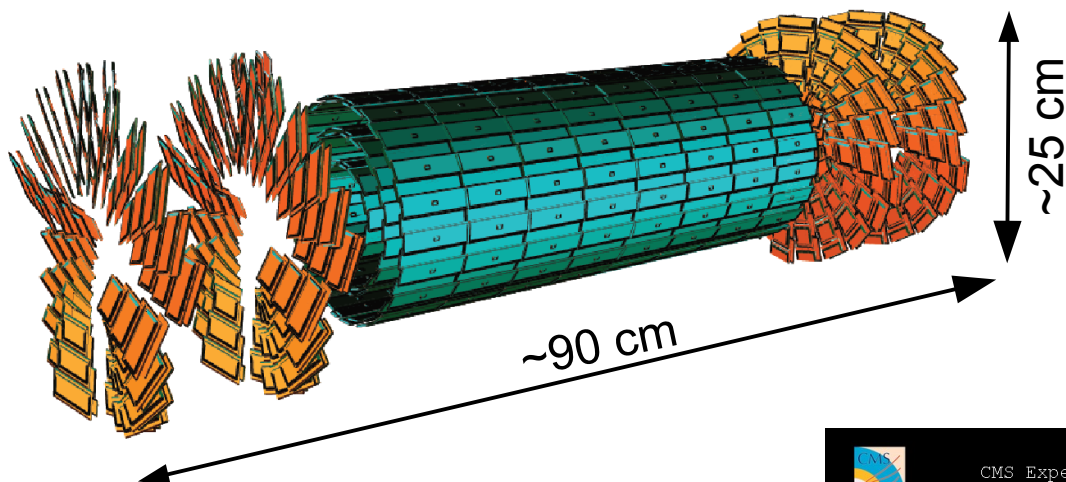


Pixel detectors



Mainly used in **tracking and vertexing**
Resolution in ~10 µm range

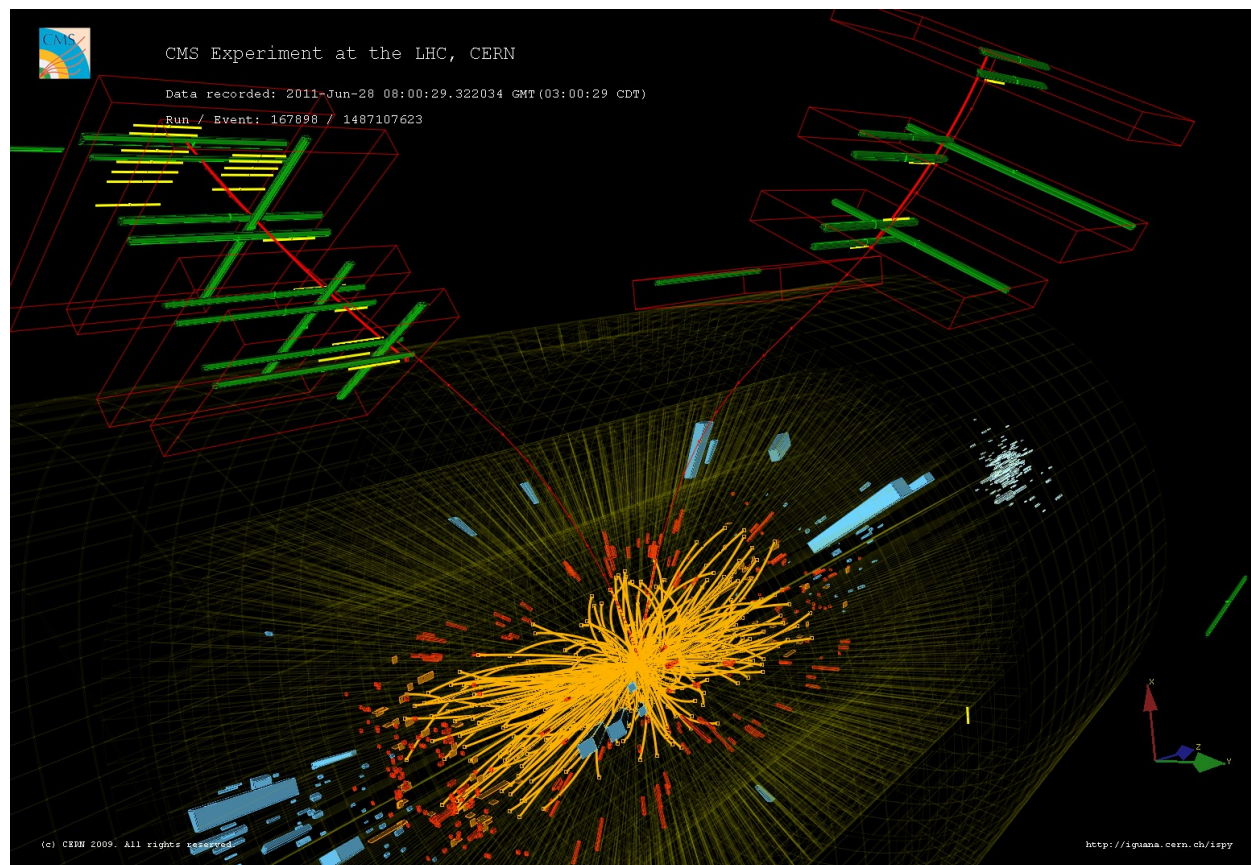
CMS pixel detector



Total area: $0.78 + 0.28 \text{ m}^2$
 3 barrel layers
 2 endcap discs
 66 million $150 \times 100 \text{ }\mu\text{m}^2$ pixels
 285 μm $\text{n}^+\text{-in-n}$ sensors
 Charge sharing driven geometry

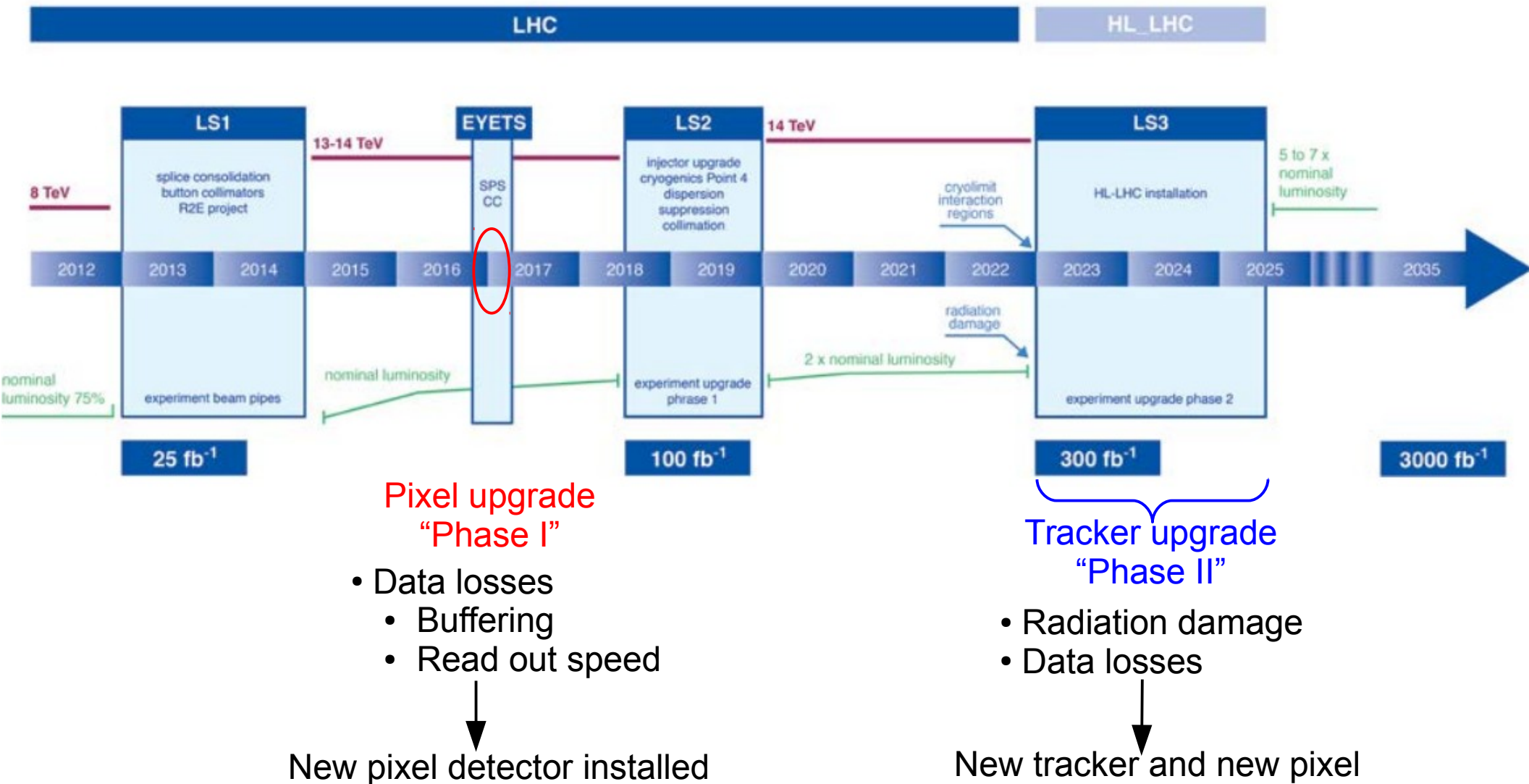
$B_s \rightarrow \mu\mu$ event

- Several sensor layers
- Cylindrical geometry
- **Measure primary and secondary vertexes**
- High track multiplicity environment
- **Fundamental for b-physics**
- **Resolution $12 \text{ }\mu\text{m}$**



LHC timetable

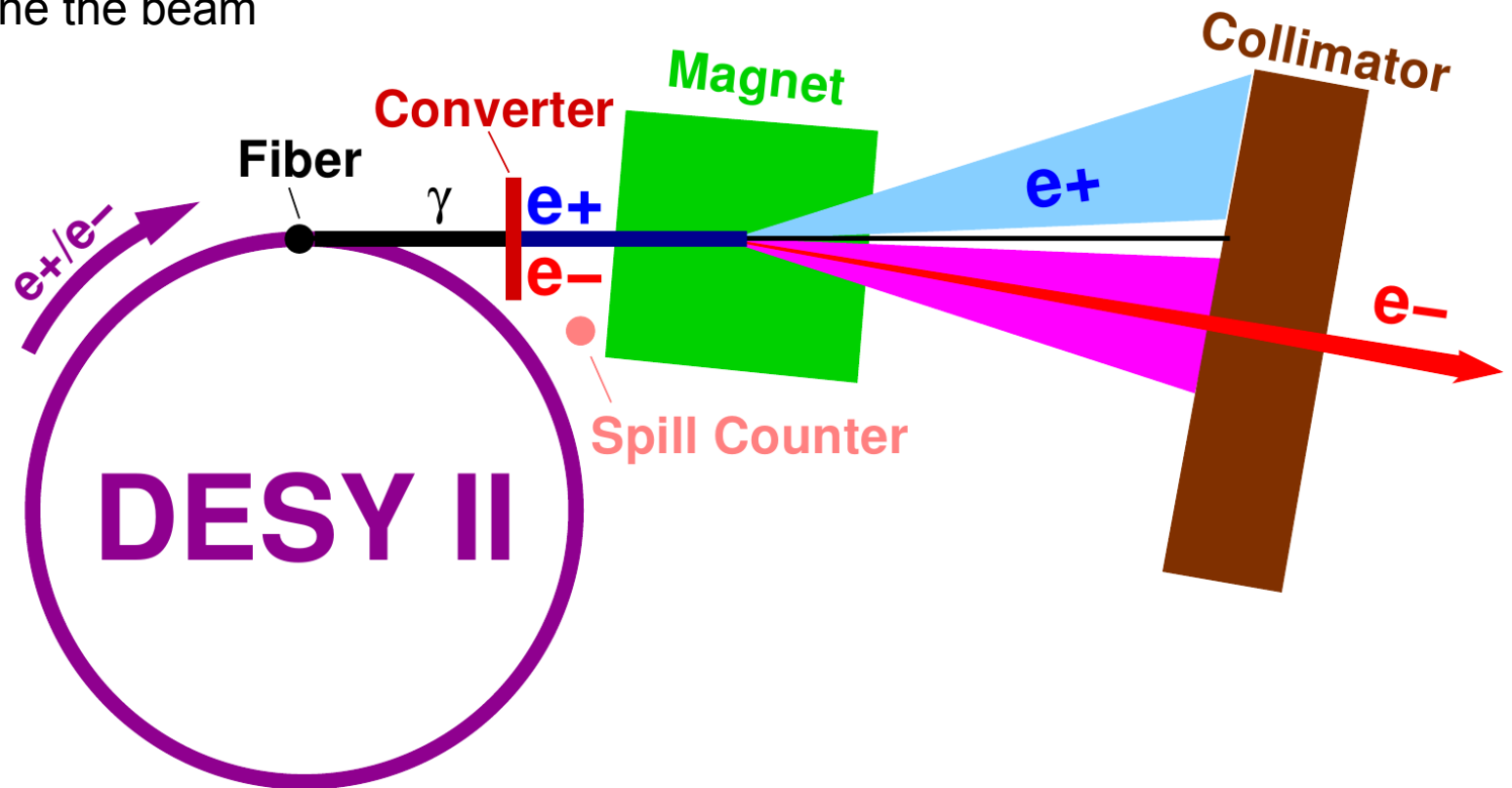
- Luminosity increase to $5 \times 10^{34} \text{ cm}^{-2}\text{s}^{-1}$
- Mean number of interaction per bunch crossing $\langle \mu \rangle \sim 140$ (every 25 ns)



Beam generation at DESY II

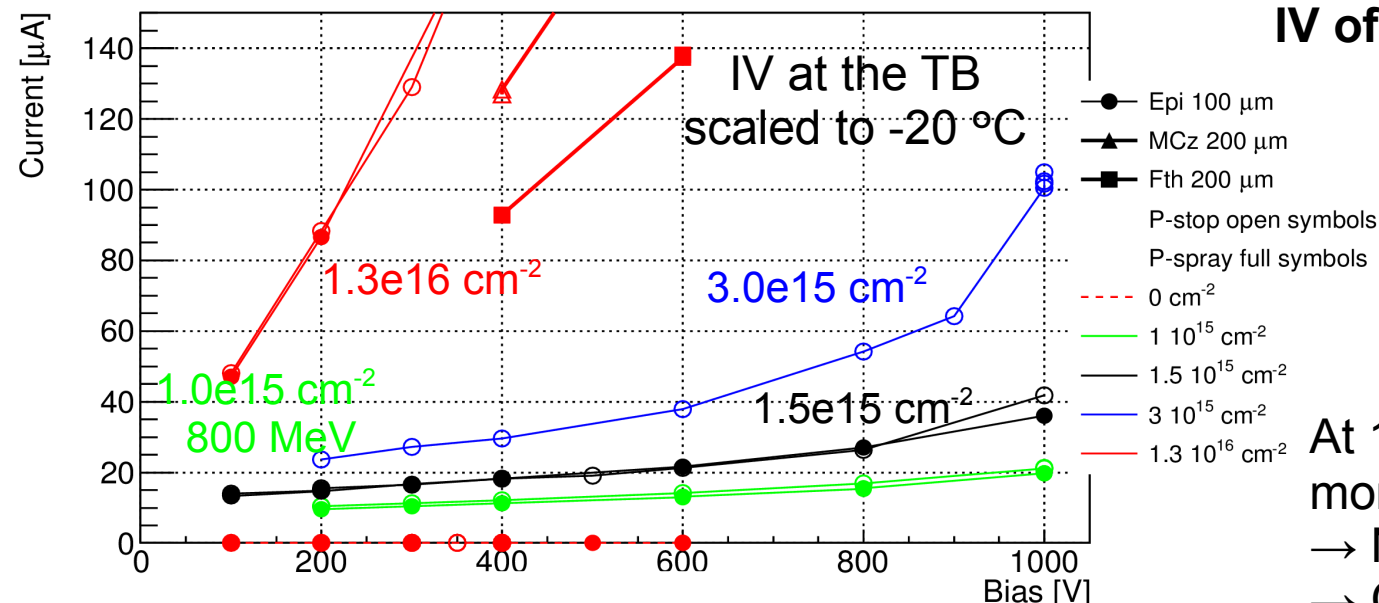
Beam generation at DESY test beam:

- Bremsstrahlung on C fiber
- Conversion in e^+e^- on a metal target
- Momentum selection using a magnet
- Collimator to define the beam



IV characteristic p-bulk sensors

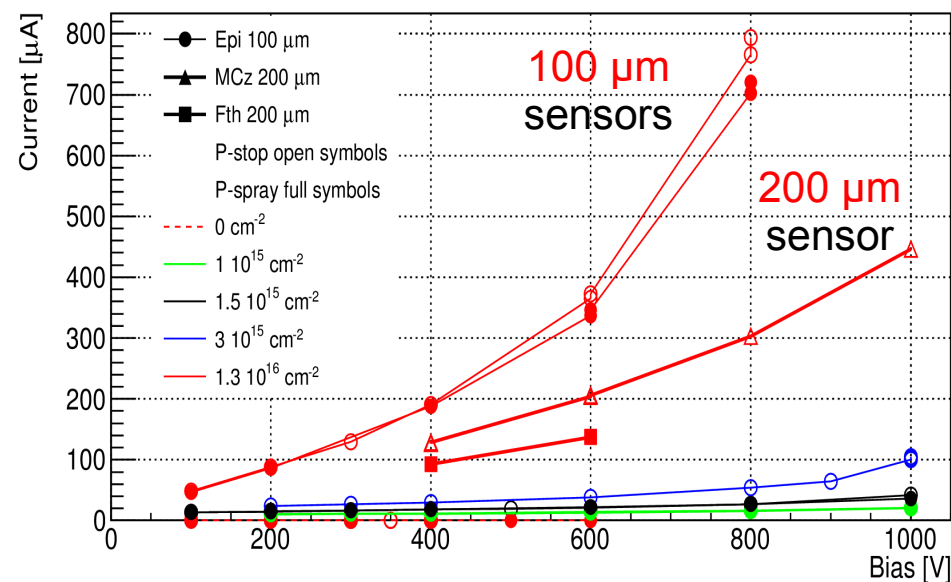
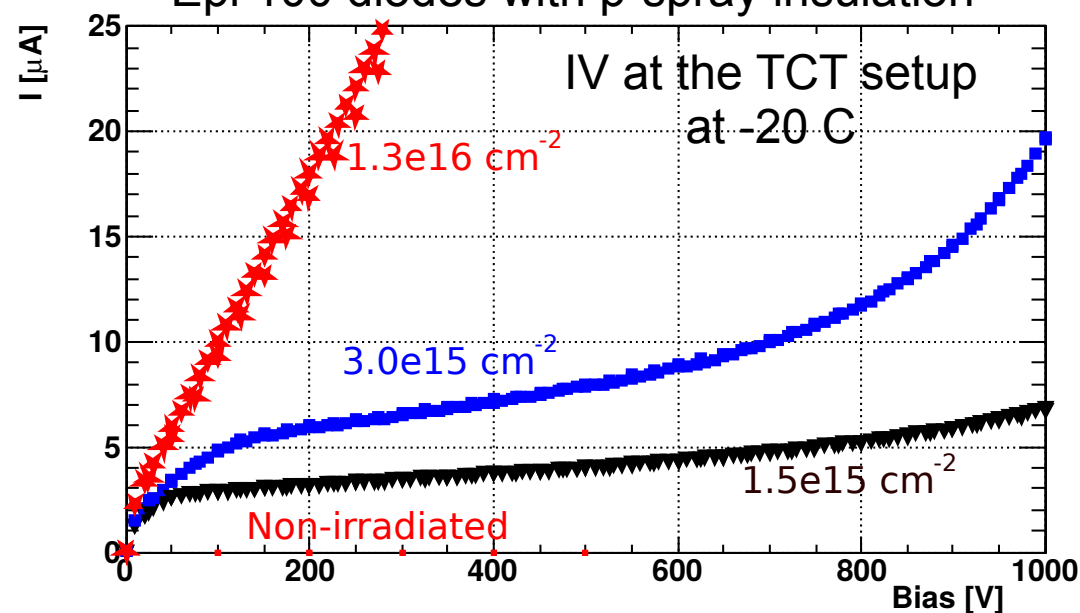
Strip sensors



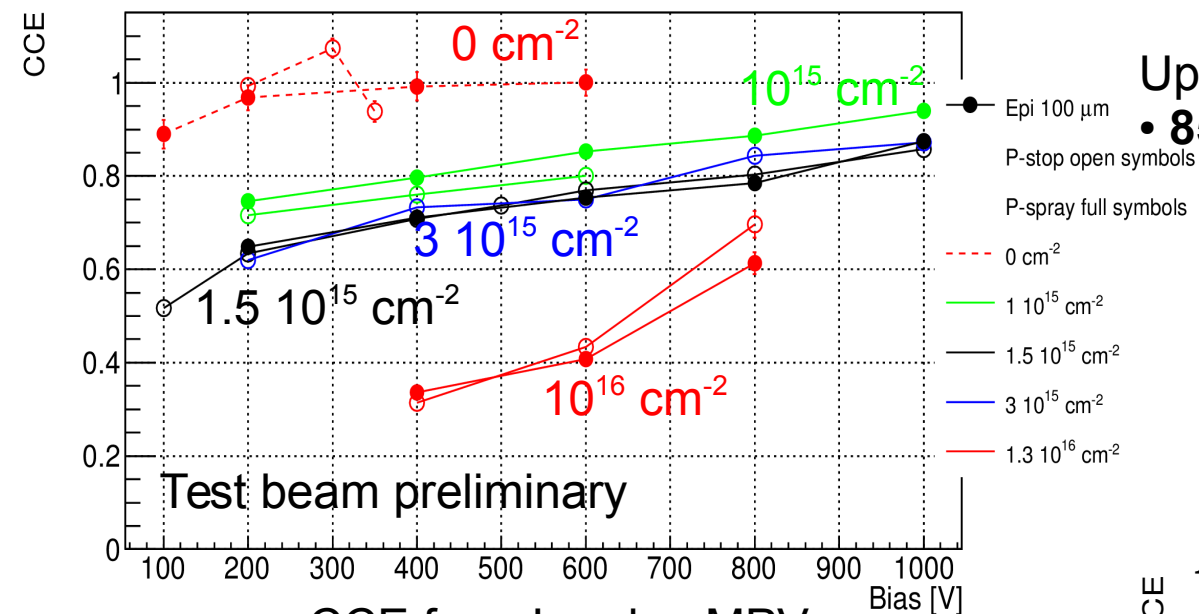
IV of both diodes and strip sensors show a “soft breakdown”

At 1.3e16 cm^{-2} 100 μm sensors draw more current than the 200 μm ones
 → No full depletion
 → Charge multiplication

Epi 100 diodes with p-spray insulation



Strip sensors at the TB



Up to $3 \times 10^{15} \text{ cm}^{-2}$:

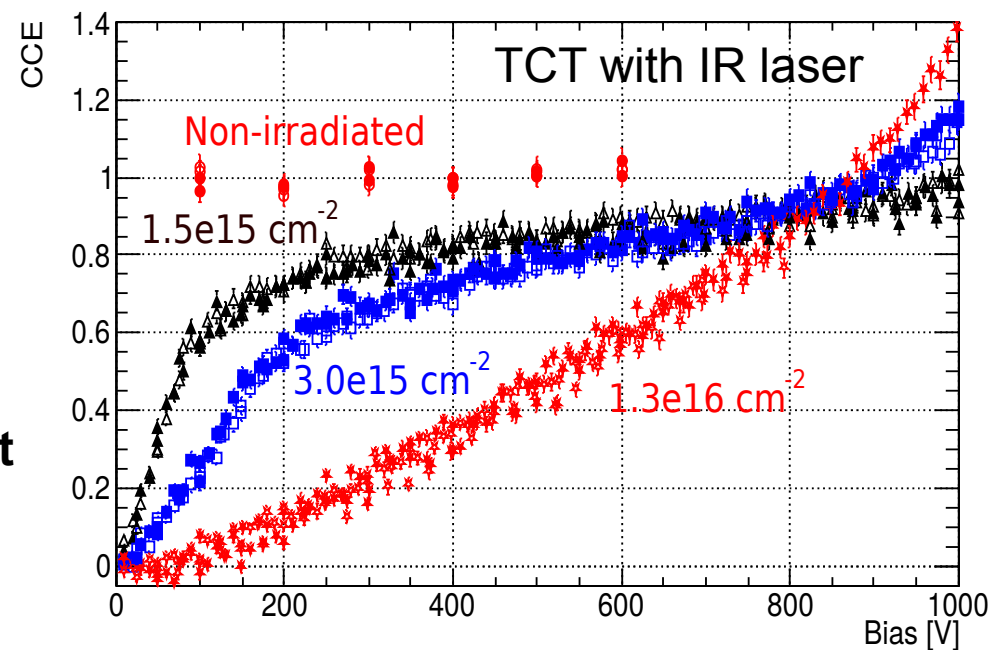
• **85% collected charge at high bias**

CCE from Landau MPV
Normalization between 200 and 400 V bias

**Difference between
TB and TCT data to be studied**

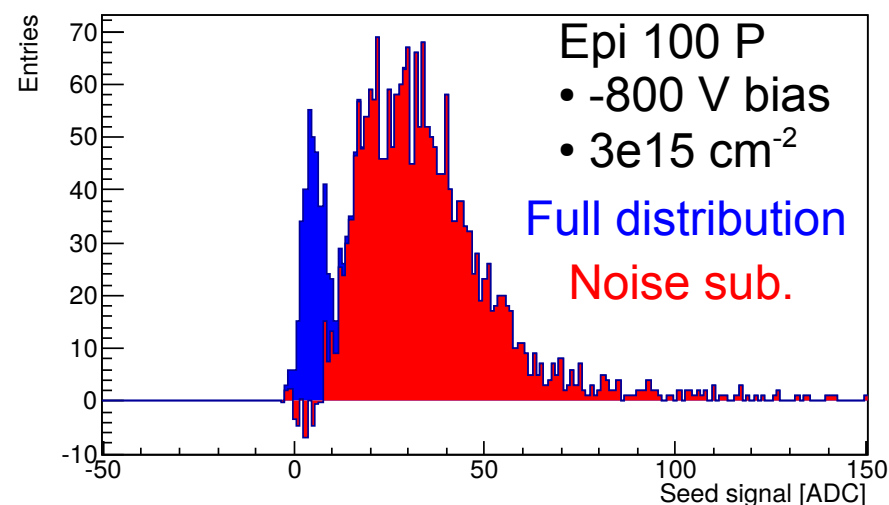
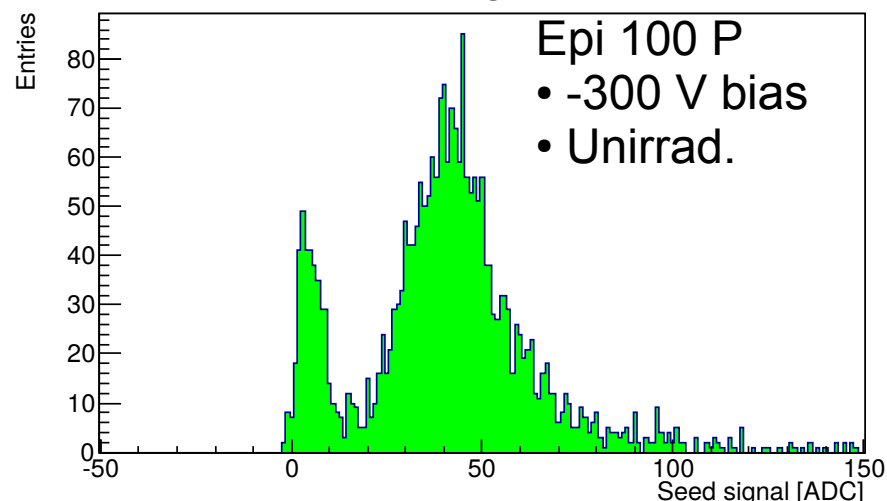
Charge multiplication in the diode measurement

Diodes with p-spray insulation



Efficiency Epi 100 p-bulk

Seed strip charge distribution



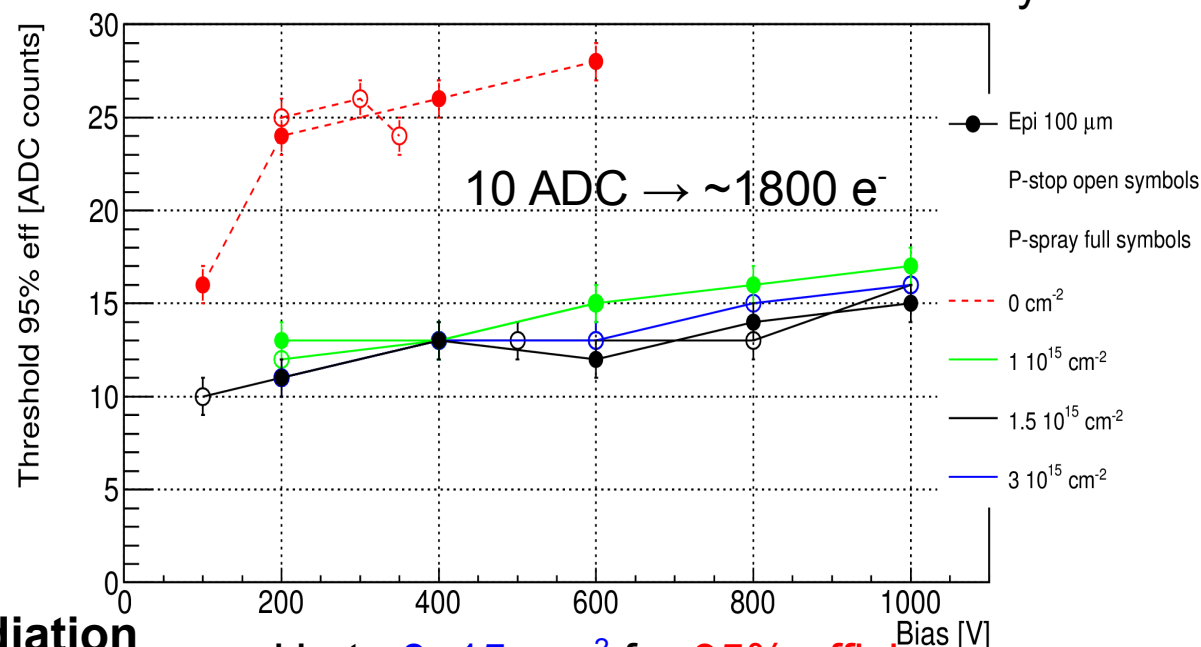
Most pixel systems use a threshold for zero suppression
→ how high can this threshold be?

CMS pixel threshold $\sim 2300 \text{ e}^-$

- Noise $< 150 \text{ e}^-$
 - Cross talk is a limiting factor
- efficiency of 99.3-99.8% (layer dependent)

This method can not access efficiency $\sim 99\%$

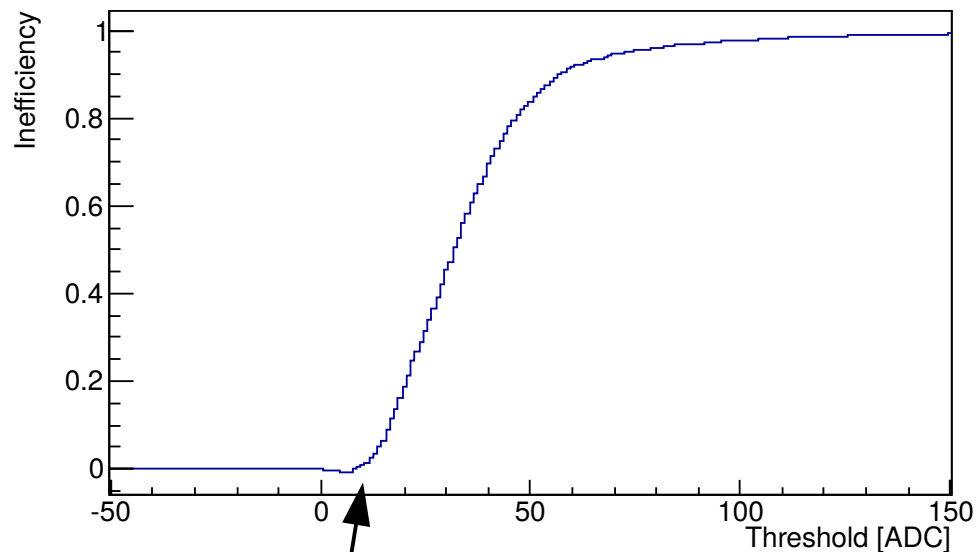
Max threshold to have 95% efficiency



The distribution gets broader with irradiation
→ influence on detection efficiency

Up to $3e15 \text{ cm}^{-2}$ for 95% efficiency:
→ Threshold $\sim 2000 \text{ e}^-$

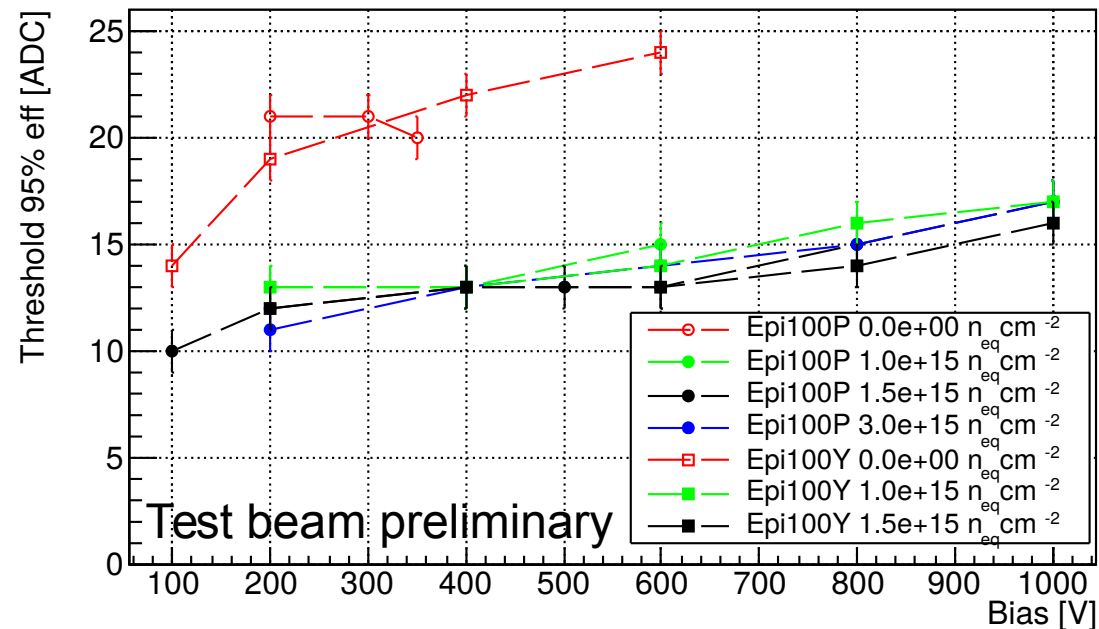
Normalized integral of **BG sub histo**



Bumps due to BG subtraction

Same plot for 99% too much influenced by bumps

Threshold to get 95% efficiency



Test beam preliminary

Oxygen content

